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Sheet	1	of	3	Attorney Docket Number	436/5

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
<i>Wen</i>	BA	International Search Report, dated 3/21/2005.			
<i>Wen</i>	BB	CHELLAPPA et al.; Human And Machine Recognition of Faces: A Survey; Proc. IEEE; May, 1995; Vol. 83; No. 5; pp. 705-740.			
<i>Wen</i>	BC	DASS et al.; Markov Face Models; The Eighth IEEE Int'l Conf. on Computer Vision; 2001; pp. 680-687.			
<i>Wen</i>	BD	HEISELE et al.; Face Detection In Still Gray Images; A.I. Memo AIM-1687; Artificial Intelligence Laboratory; May 2000; pp. 1-25.			
<i>Wen</i>	BE	HJELMAS et al.; Face Detection: A Survey; Computer Vision and Image Understanding; 2001; Vol. 83; pp. 236-274.			
<i>Wen</i>	BF	P. HO; Rotation Invariant Real-Time Face Detection And Recognition System; A.I. Memo AIM-2001-010; 05/31/01; Artificial Intelligence Lab.; pp. 1-24.			
<i>Wen</i>	BG	HSU et al.; Face Detection In Color Images; Int'l Conference on Image Processing; 2001; pp. 1046-1049.			
<i>Wen</i>	BH	LIU et al.; Evolutionary Pursuit And Its Application To Face Recognition; IEEE Trans. Pattern Analysis and Machine Intelligence; 2000; Vol. 22; No. 6; pp. 570-582.			
<i>Wen</i>	BI	LIU et al.; Robust Coding Schemes For Indexing And Retrieval From Large Face Databases; IEEE Trans. on Image Proc.; 2000; Vol. 9; No. 1; pp. 1-16.			
<i>Wen</i>	BJ	LIU et al.; A Shape And Texture Based Enhanced Fisher Classifier For Face Recognition; IEEE Trans. on Image Proc.; 2001; Vol. 10; No. 4; pp. 1-35.			

Examiner Signature	WENPENG CHEN PRIMARY EXAMINER	Date Considered	5/19/05
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Substitute for form 1449/PTO		Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Application Number	10/766,121		
		Filing Date	January 27, 2004		
		First Named Inventor	Chengjun Liu		
		Art Unit	2624		
		Examiner Name	Wenpeng Chen		
Sheet	2	of	3	Attorney Docket Number	436/5

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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
<i>Wen</i>	BK	LIU et al.; Gabor Feature Based Classification Using The Enhanced Fisher Linear Discriminant Model For Face Rec.; IEEE Trans. on Image Proc.; 2002; Vol 11; No. 4; pp. 1-36.			
<i>Wen</i>	BL	MOGHADDAM et al.; Probabilistic Visual Learning For Object Representation; IEEE Trans. Pattern Analysis and Machine Intelligence; 1997; Vol. 19; No.7; pp. 1-31.			
<i>Wen</i>	BM	MOHAN et al.; Example-Based Object Detection In Images By Components; IEEE Trans. Pattern Analysis and Machine Intelligence; 2001; Vol. 23; No. 4; pp. 349-361.			
<i>Wen</i>	BN	PAPAGEORGIOU et al.; A General Framework For Object Detection; Int'l Conference on Computer Vision; Jan. 1998; pp. 555-562.			
<i>Wen</i>	BO	PENTLAND et al.; View-Based And Modular Eigenspaces For Face Recognition; Proc. Computer Vision and Pattern Recognition; 1994; pp. 84-91.			
<i>Wen</i>	BP	PHILLIPS et al.; The Feret Database And Evaluation Procedure For Face-Recognition Algorithms; Image and Vision Computing; 1998; Vol. 16; pp. 295-306.			
<i>Wen</i>	BQ	Qian et al.; Object Detection Using Hierarchical MRF and MAP Estimation; Proc. Computer Vision and Pattern Recognition; 1997; pp. 186-192.			
<i>Wen</i>	BR	ROWLEY et al.; Neural Network-Based Face Detection; IEEE Trans. Pattern Analysis and Machine Intelligence; 1998; Vol. 20; No. 1; pp. 1-28.			
<i>Wen</i>	BS	ROWLEY et al.; Rotation Invariant Neural Network-Based Face Detection; Proc. IEEE Computer Society Conf. on Computer Vision and Pattern Recognition; 1998; pp. 38-44.			
<i>Wen</i>	BT	SAMAL et al.; Automatic Recognition And Analysis Of Human Faces And Facial Expressions: A Survey; Pattern Recognition; 1992; Vol. 25; No. 1; pp. 65-77.			

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STATEMENT BY APPLICANT

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Sheet

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of

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Complete if Known

Application Number	10/766,121
Filing Date	January 27, 2004
First Named Inventor	Chengjun Liu
Art Unit	2624
Examiner Name	Wenpeng Chen

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<i>ml</i>	BU	SCHNEIDERMAN et al.; Probabilistic Modeling Of Local Appearance And Spatial Relationships For...; Proc. IEEE Computer Society Conf. on Computer Vision and...; 1998; pp. 1-7.	
<i>ml</i>	BV	SCHNEIDERMAN et al.; A Statistical Method For 3D Object Detection Applied To Faces And Cars; Proc. IEEE Computer Society Conf. on Computer Vision and Pattern..., 2000; pp 1-6.	
<i>ml</i>	BW	SUNG et al.; Learning And Example Selection For Object And Pattern Detection; A.I.T.R. No. 1572; MIT; Jan. 1996; pp. 1-195.	
<i>ml</i>	BX	SUNG et al.; Example-Based Learning For View-Based Human Face Detection; IEEE Trans. Pattern Analysis and Machine intelligence; 1998; Vol. 20; No. 1; pp. 39-51.	
<i>ml</i>	BY	VIOLA et al.; Rapid Object Detection Using A Boosted Cascade Of Simple Features; Proc. IEEE Computer Society Conf. on Computer Vision and Pattern Recognition; 2001; pp. 1-9.	
<i>ml</i>	BZ	YANG et al.; Face Detection Using Mixtures Of Linear Subspaces; Proc. Fifth Int'l Conf. on Automatic Face and Gesture Recognition; March 2000; pp. 1-7.	
<i>ml</i>	CA	A. YUILLE; Deformable Templates For Face Recognition; Journal of Cognitive Neuroscience; 1991; Vol. 3; No. 1; pp. 59-70.	
<i>ml</i>	CB	K. FUKUNAGA; Introduction to Statistical Pattern Recognition; Second Edition, pp. 51-253 and 399-507.	

Examiner Signature	WENPENG CHEN PRIMARY EXAMINER <i>Wenpeng Chen</i>	Date Considered	5/19/05
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